

A Solution-Processed n-Doped Fullerene Cathode Interfacial Layer for Efficient and Stable Large-Area Perovskite Solar Cells

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A novel solution-processed cetyltrimethylammonium bromide (CTAB)-doped [6,6]-phenyl-C₆₁-butyric acid methyl ester (PC₆₁BM) film prepared by an extremely facile method is demonstrated as an effective cathode interfacial layer for perovskite solar cells (PSCs). This doped layer also exerts multi-positive effects for use in PSCs, including efficient interfacial charge transfer ability, superior charge selectivity, good film coverage on the perovskite layer, relatively weak thickness-dependent performance properties, general applicability to different perovskite materials, and good ambient stability. With this n-doped PC₆₁BM layer, the device delivers high power conversion efficiency (PCE) up to 17.1%. The application of the CTAB-doped PC₆₁BM layer in large-area solar cells (active area = 1.2 cm²) is also demonstrated, and a remarkable PCE of 15.4% is achieved, which represents one of the highest PCE values for PSCs with a similar active area. More significantly, the resulting devices possess good ambient stability without the need for rigorous encapsulation.

Introduction

Hybrid organic-inorganic lead halide perovskite solar cells (PSCs) hold much promise for cost-effective solar energy.

Commonly used planar heterojunction device configuration: ITO-coated glass/PEDOT:PSS/perovskite/PC₆₁BM ETL/cathode

Main challenge in PSCs: poor stability due in part to the use of low work-function (WF) metals (e.g. Ca or Al) as the cathode.

High WF metals (e.g. Ag or Au) ⇒ existence of energy barrier at metal/PC₆₁BM interface ⇒ low power conversion efficiency (PCE)

An effective strategy is to incorporate an additional cathode buffer layer (CBL) between PC₆₁BM ETL and high WF cathode.

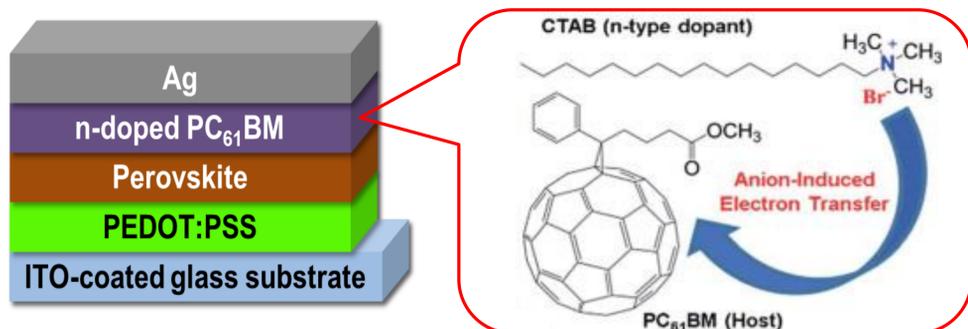
This certainly increases fabrication complexity due to the requirements of additional steps and accurate layer thicknesses

Deposition of uniform and ultrathin CBL (5-25 nm) on rough PC₆₁BM/perovskite surface without pinholes remains challenging

This work : we demonstrate an effective strategy to improve PCE & stability through facile chemical doping (n-doping) of PC₆₁BM:

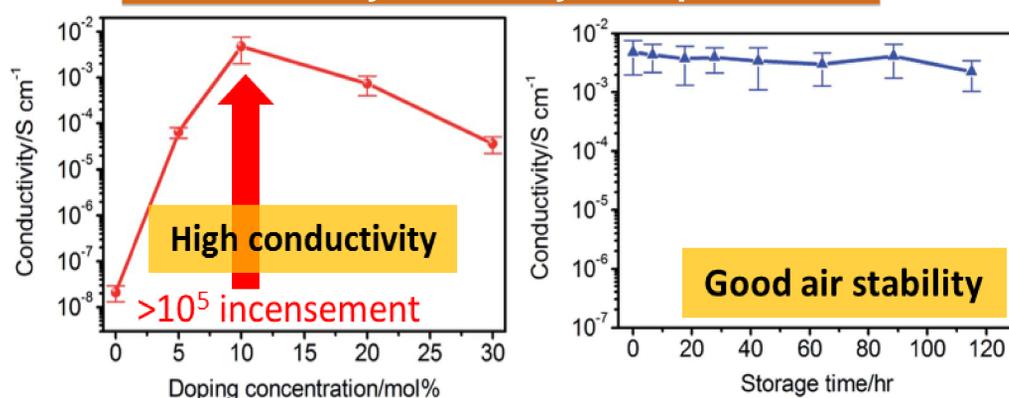
The doped film is capable of serving as both ETL & CBL in PSCs

Experimental

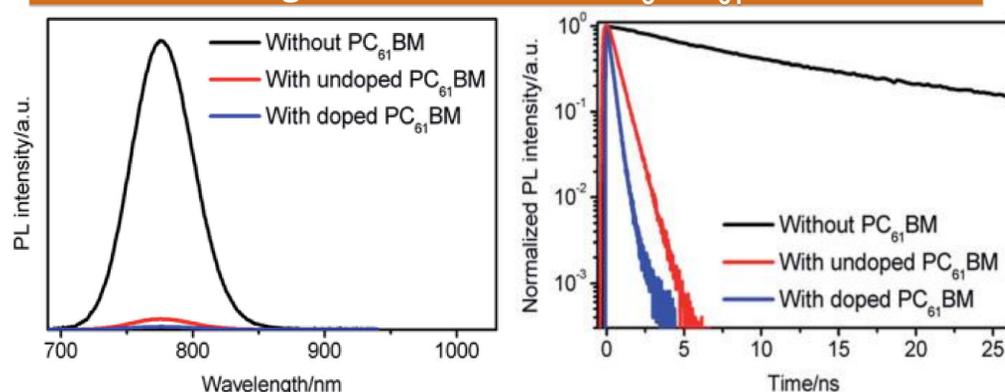


Result and Discussion

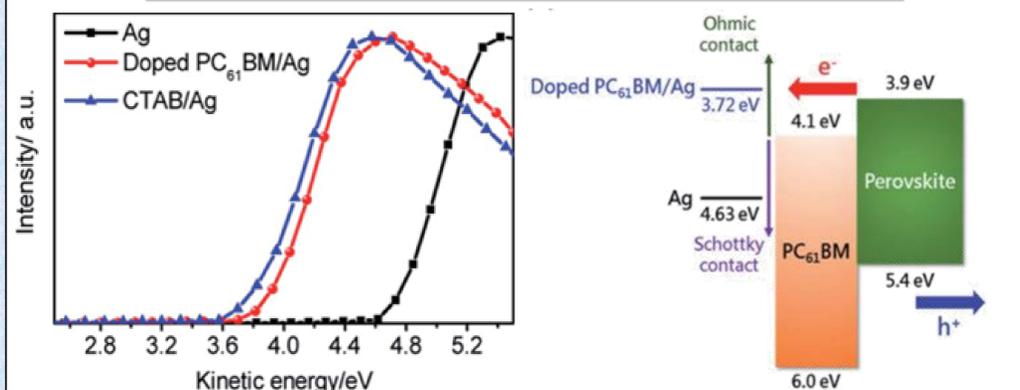
Conductivity & stability of doped films



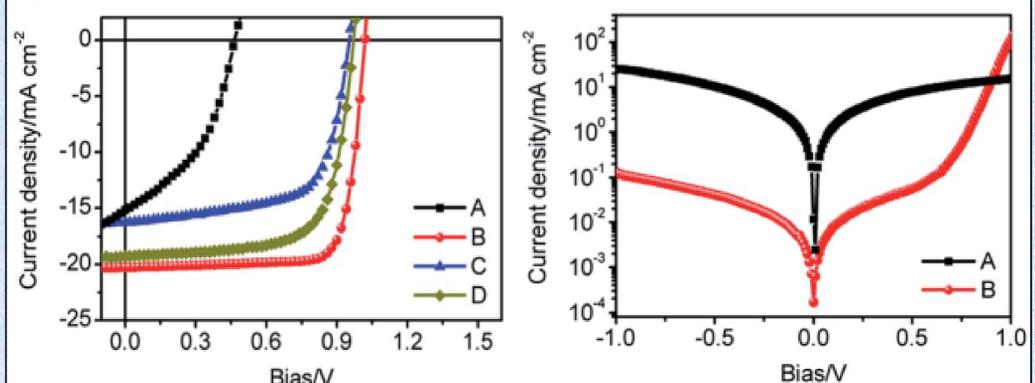
Efficient charge transfer at MAPbI₃/PC₆₁BM interface



WF modulation of Ag electrode

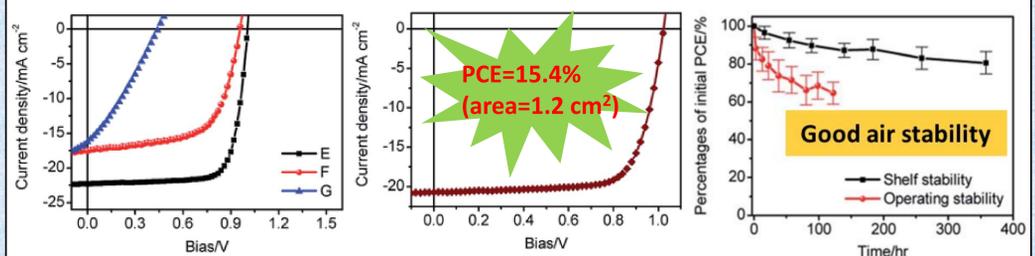


J-V characteristics of MAPbI₃-based devices



Device	Interfacial layer	V _{oc} [volt]	J _{sc} [mA cm ⁻²]	FF [%]	PCE [%]
A	PC ₆₁ BM	0.47	15.14	42.60	3.0
B	Doped PC ₆₁ BM	1.01	20.27	78.75	16.1
C	PC ₆₁ BM/ZnO	0.95	16.29	66.13	10.2
D	PC ₆₁ BM/CTAB	0.97	19.27	70.16	13.1

J-V characteristics & stability of FAPbI₃-based devices



Device	Interfacial layer	V _{oc} [volt]	J _{sc} [mA cm ⁻²]	FF [%]	PCE [%]
E	Doped PC ₆₁ BM	1.01	22.41	75.60	17.1
F	PC ₆₁ BM	0.45	16.28	29.27	2.2
G	PC ₆₁ BM/ZnO	0.95	17.55	62.67	10.5

Conclusion

A promising method to improve PCE & stability of PSCs is demonstrated by using CTAB-doped PC₆₁BM as CBL and ETL:

- Remarkable PCE up to 17.1% is demonstrated
- Record-high PCE of 15.4% is obtained for large device (1.2 cm²)
- Good ambient stability is achieved without encapsulation

Reference

Chih-Yu Chang, Wen-Kuan Huang, Yu-Chia Chang, Kuan-Ting Lee, Chin-Ti Chen, *J. Mater. Chem. A*, 2016, 4, 640–648.